

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/686,705 SAWANAGA ET AL.	
		Examiner	Art Unit	Page 1 of 1 Tran Nguyen 3626

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*	C	US-6,381,557	04-2002	Babula et al.	702/183
*	D	US-6,735,549	05-2004	Ridolfo, Charles F.	702/181
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.